

Notice of References Cited	Application/Control No. 10/521,156	Applicant(s)/Patent Under Reexamination AMEMIYA ET AL.	
	Examiner KEVIN Y. KIM	Art Unit 3714	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,119,229 A	09-2000	Martinez et al.	726/28
*	B	US-2001/0032252 A1	10-2001	Durst et al.	709/218
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
	O					
	P					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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